

**Notice of References Cited**

Application/Control No.

09/582,495

Applicant(s)/Patent Under  
Reexamination  
OHGA ET AL.

Examiner

Hector M Reyes

Art Unit

1623

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US- -			
	B	US- -			
	C	US- -			
	D	US- -			
	E	US- -			
	F	US- -			
	G	US- -			
	H	US- -			
	I	US- -			
	J	US- -			
	K	US- -			
	L	US- -			
	M	US- -			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-09194427-	07-1997	Japan	Takada et al	
	O	- -				
	P	- -				
	Q	- -				
	R	- -				
	S	- -				
	T	- -				

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Aldrich Catalog, Handbook of Fine Chemicals, 1996-97
	V	Jiang, Cuanyu; Zhang, Xiankang; Du, Jianpin; Hua, Jiandong, Fang, Shibi; Jiang, Yingyan, Shanghai Keji Daxue Xuebao (Journal of Shanghai University of Science and Technology), no. 1, pages 81-87, 1987.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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